

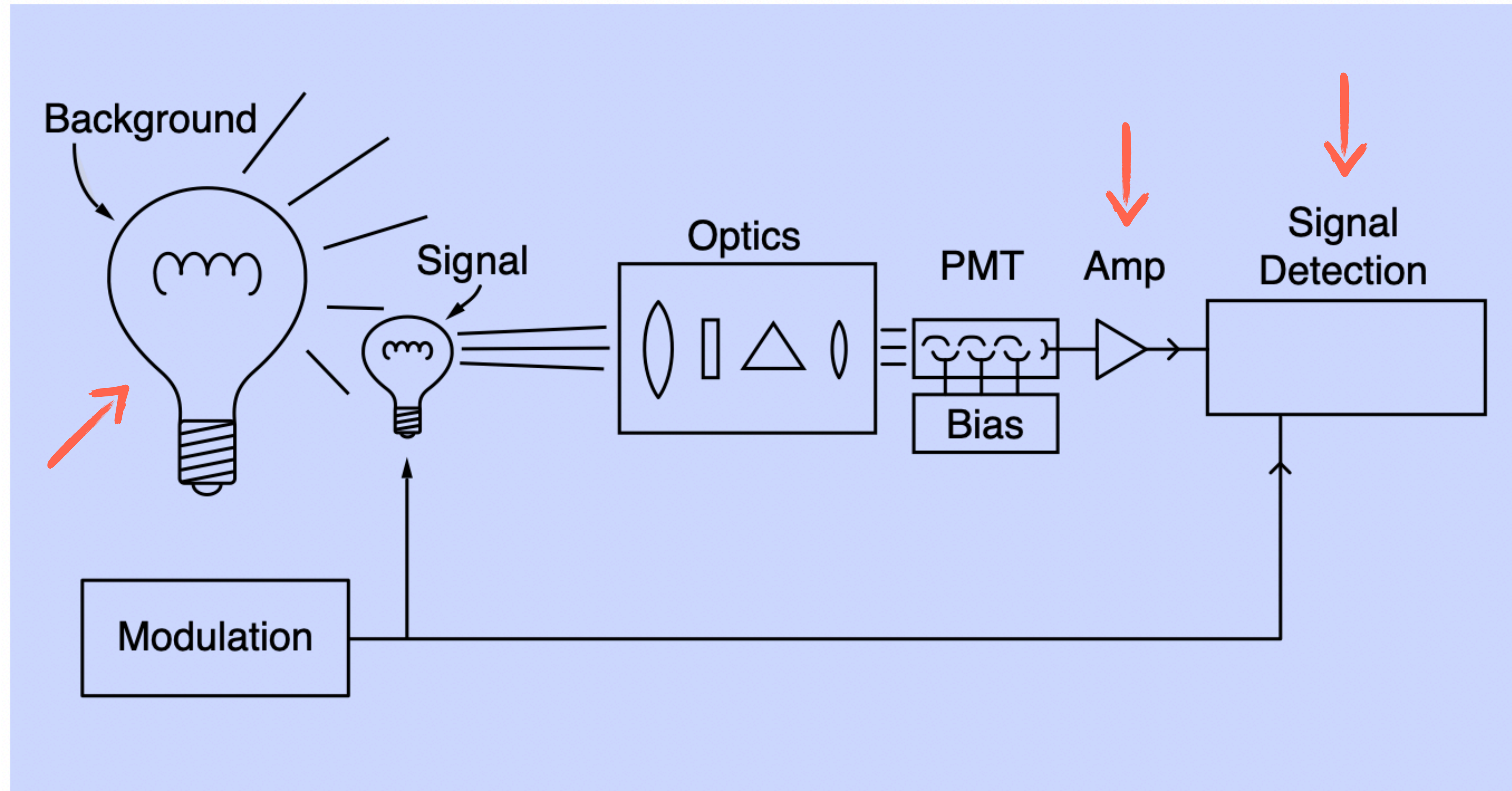
Recovering signals out of noise: the lock-in amplifier

Laboratorio di Fisica della Materia Condensata, a.a. 2024/25

Noise is ubiquitous in experiments!

- * Almost all measurements are done using electronic equipment. This means that experimental techniques rely on the **quantitative measurement of electrons** (voltages, currents, charge etc.)
 - E.g. measurement of a DC anode current by an ampèremeter, charge counting in the pixels of a charge-coupled device (CCD) camera chip, ...
- * Any electronic signal always shows random, uncorrelated fluctuations: **noise**
- * The signal of interest may be **obscured by noise**! The noise may be fundamental to the process: e.g. discrete charges (as well as discrete light quanta, i.e. photons) are governed by Poisson statistics which gives rise to shot noise.

Prototype experiment



Two types of noise

- * Sometimes noise is **extrinsic** and “**non-essential**”: it can be minimised by good laboratory practice
- * Often noise sources are **intrinsic**, related to the physics (and the statistics) of the system and the probe used in the measurements: this cannot be acted upon

Intrinsic sources of noise:

- Shot noise
 - Johnson-Nyquist noise
 - Flicker noise (aka $1/f$ noise)
- * Understanding the noise sources in a measurement is critical to achieving a satisfactory signal-to-noise performance! → The quality of a measurement may be substantially degraded by a trivial error...

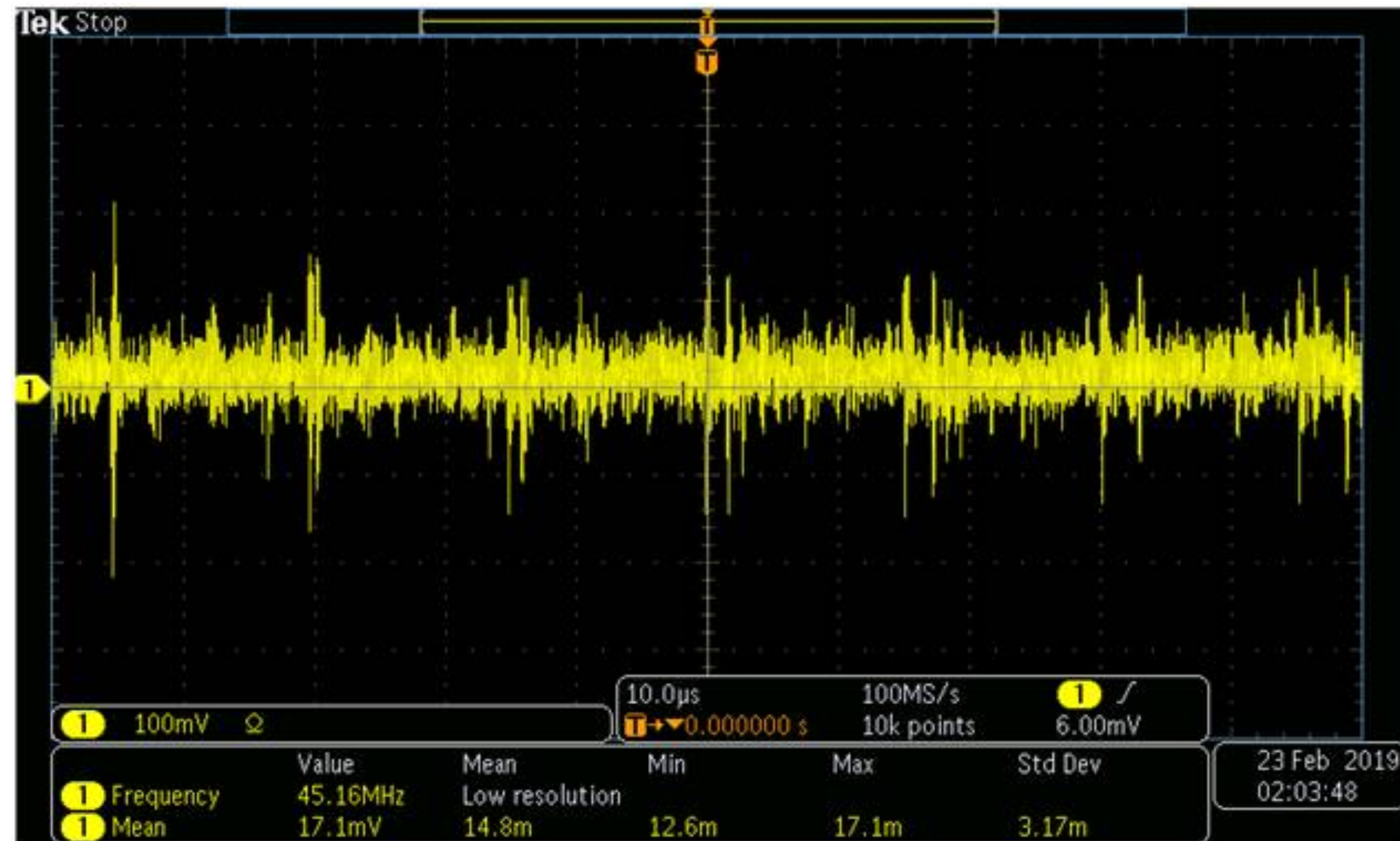
Spectral noise density

- * Noise characteristics of a system are often represented by the noise spectral density (PSD)
- * Let's consider a quantity of interest $X(t)$: the PSD $S_X(f)$ is defined as the squared modulus of the Fourier transform of $X(t)$

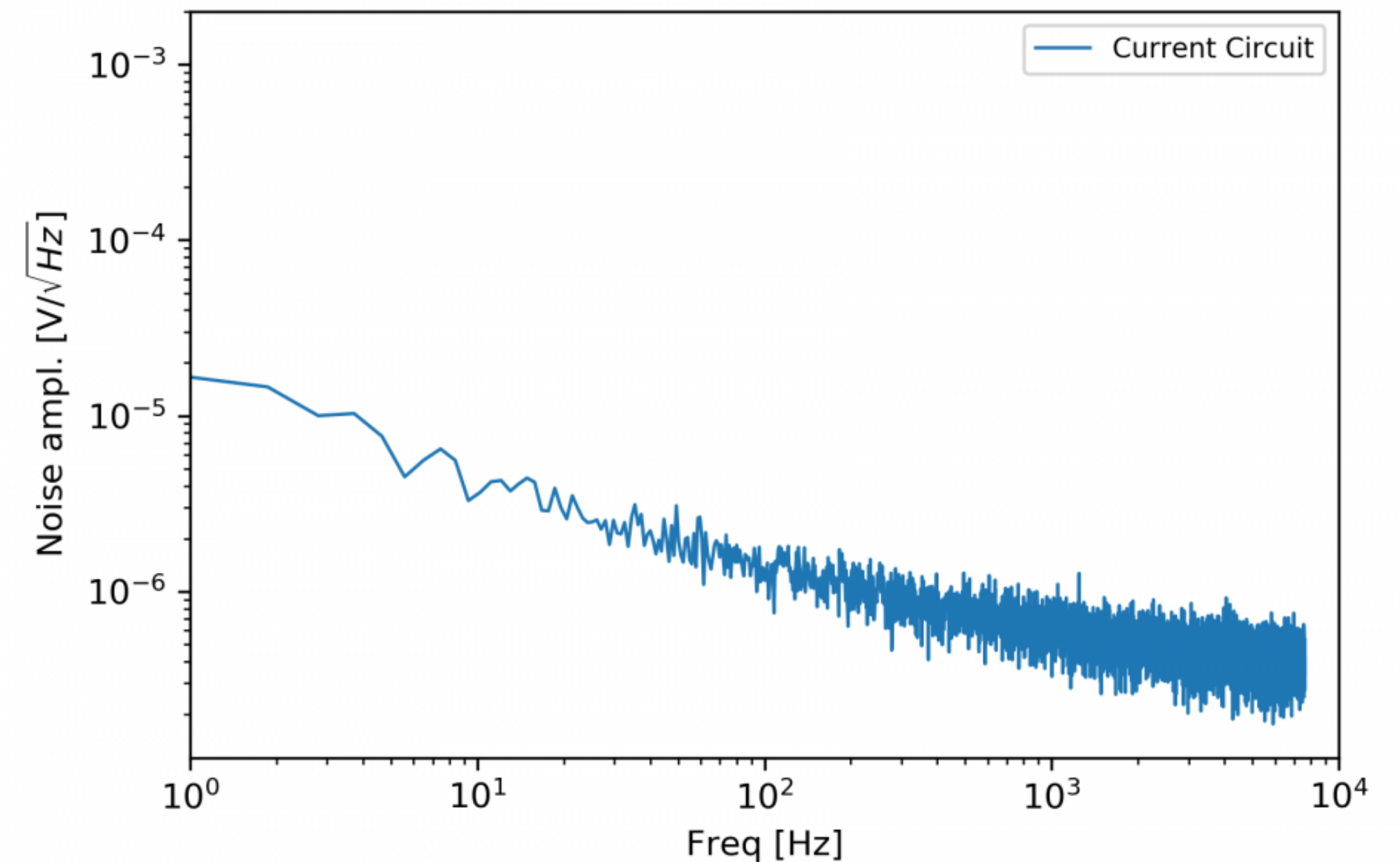
$$S_X(f) = \lim_{T \rightarrow \infty} \frac{1}{T} \left\langle \left| \int_{-T/2}^{+T/2} X(t) e^{+i2\pi ft} dt \right|^2 \right\rangle$$

- * PSDs are statistical measures: they can be estimated from real data by averaging over many measurements → Taking a single measurement trace gives only a rough estimate of the PSD

Noise PSD in practice...



FT
→

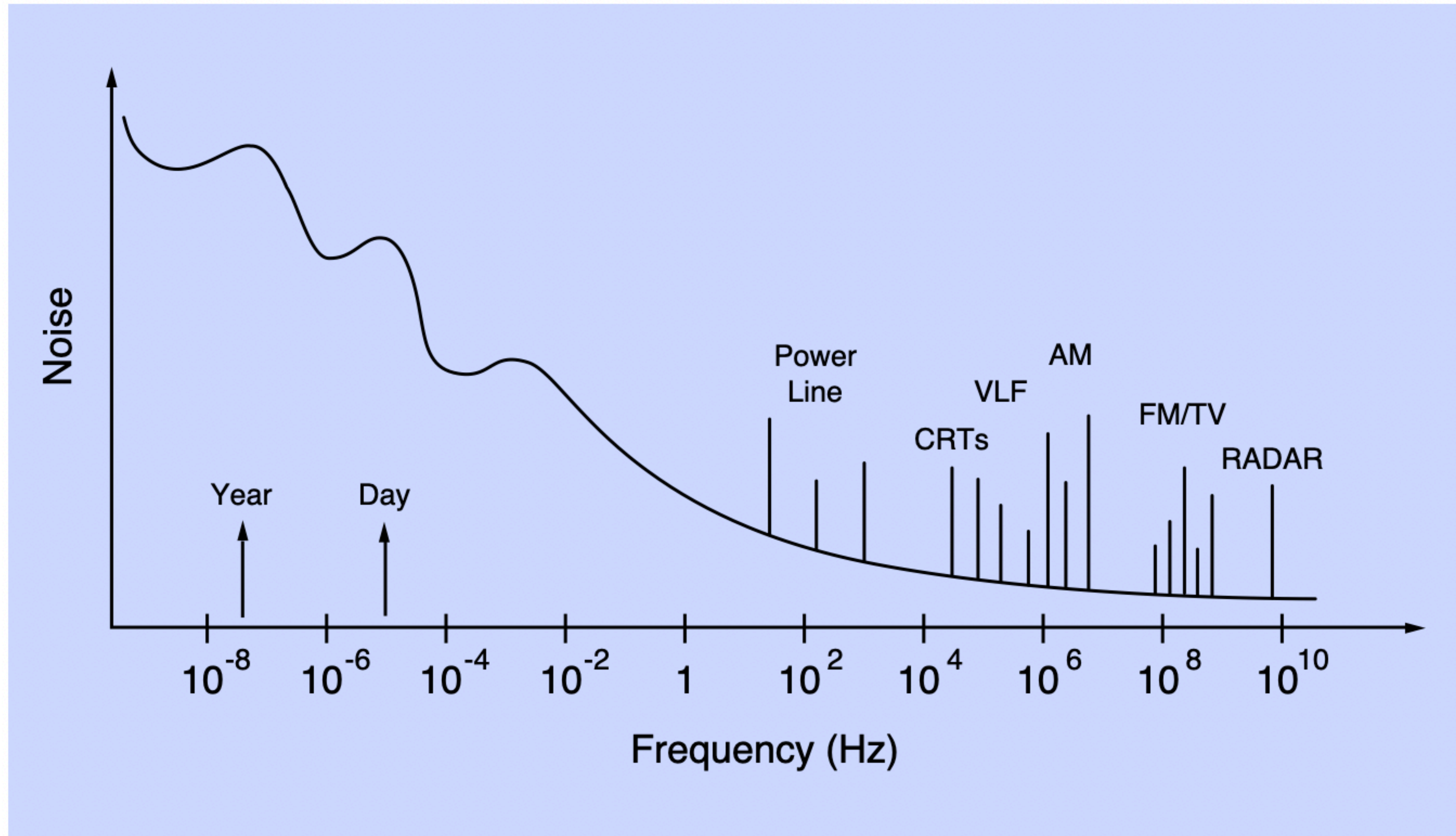


Remove signal mean,
only fluctuations around the mean

Units of $V/\sqrt{\text{Hz}}$

An RMS is obtained by integrating the
PSD over a chosen frequency window

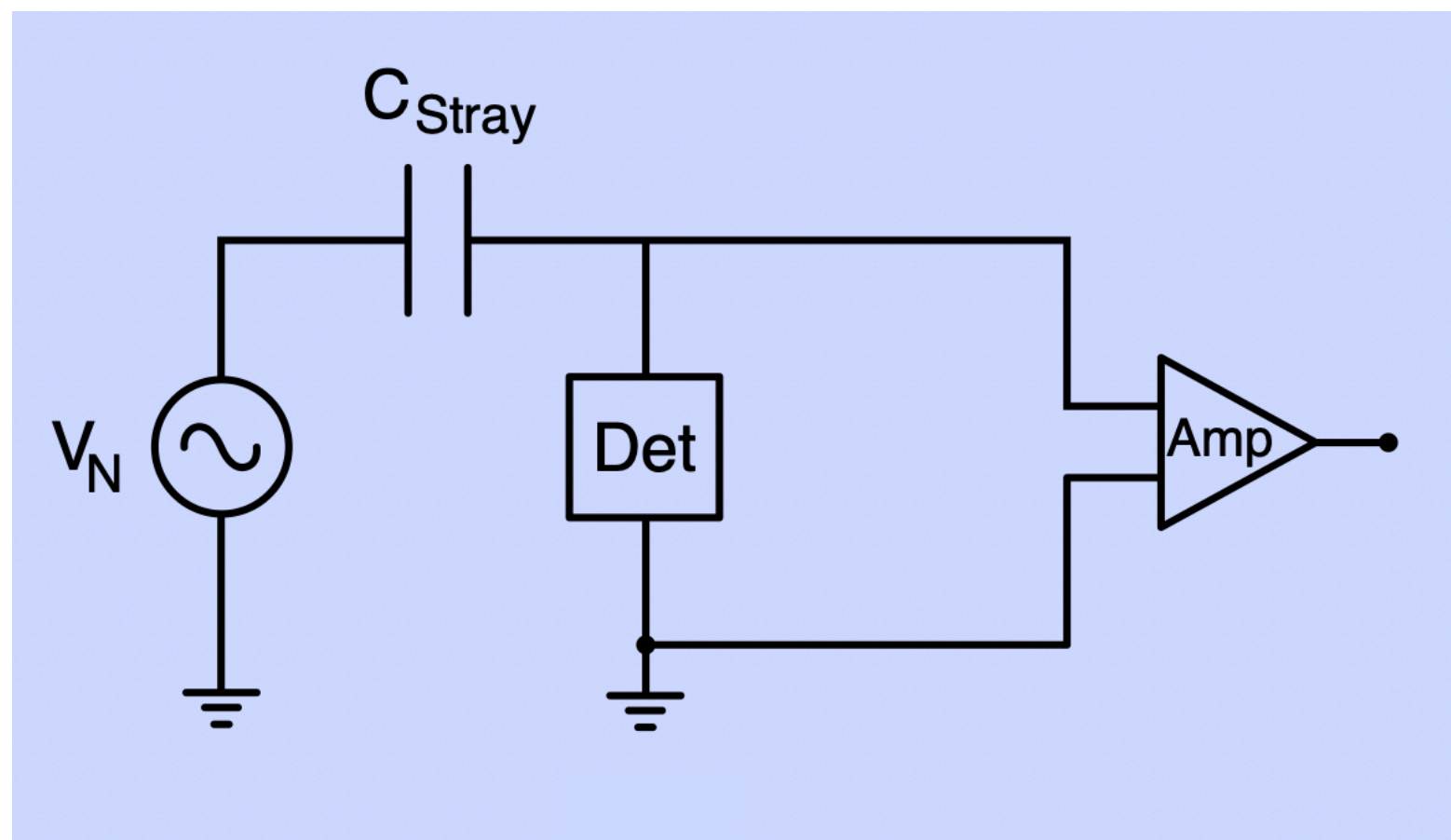
Examples of PSD and noise sources



Examples of extrinsic noise sources

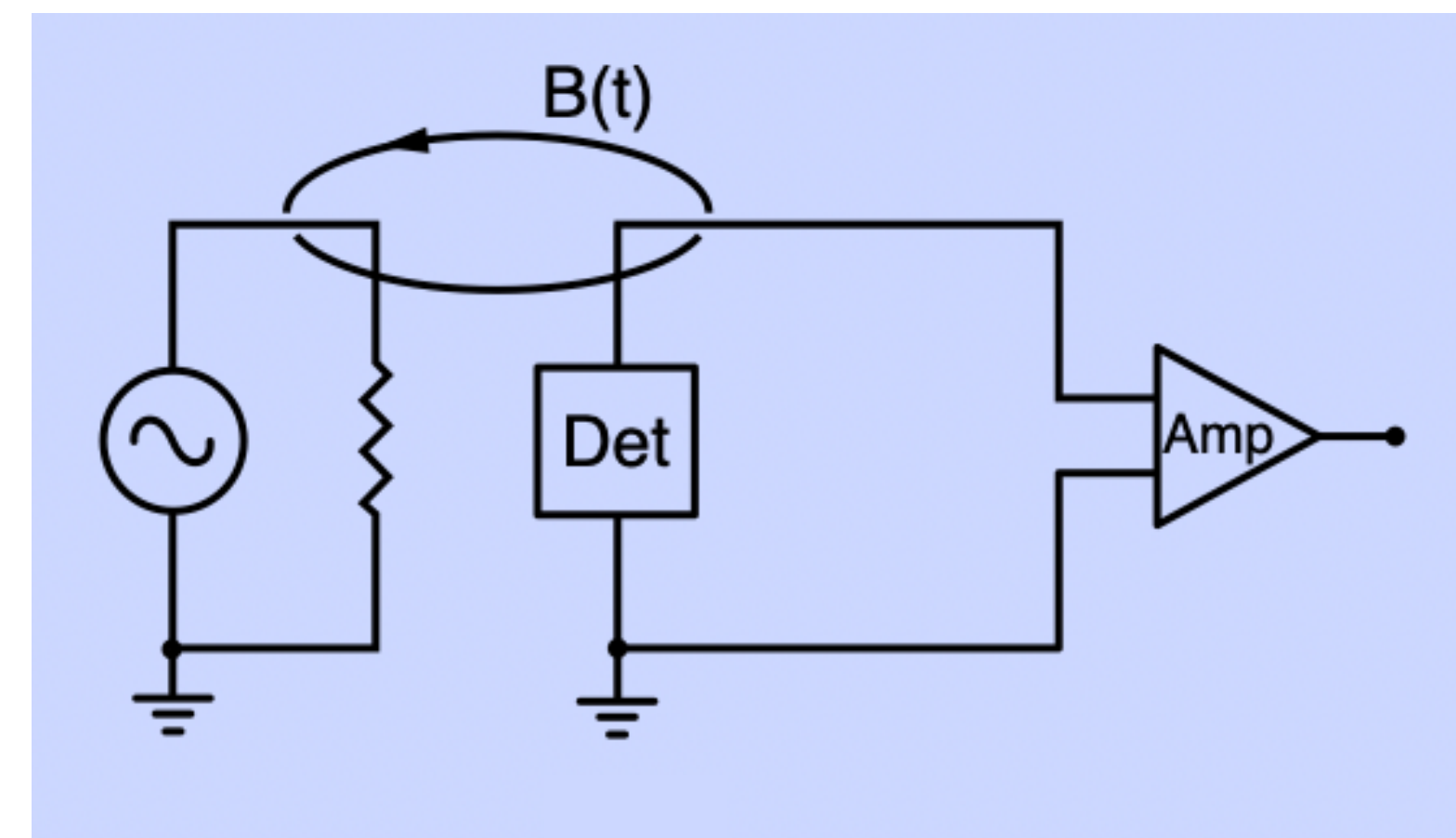
Capacitive and inductive couplings

- * Noise can be picked up through the **capacitive coupling** with a nearby apparatus with varying voltage



Cure: shielding the detector

- * Noise can be picked up through the **inductive coupling** to a time-varying magnetic field, which induces a e.m.f. in the detection circuit



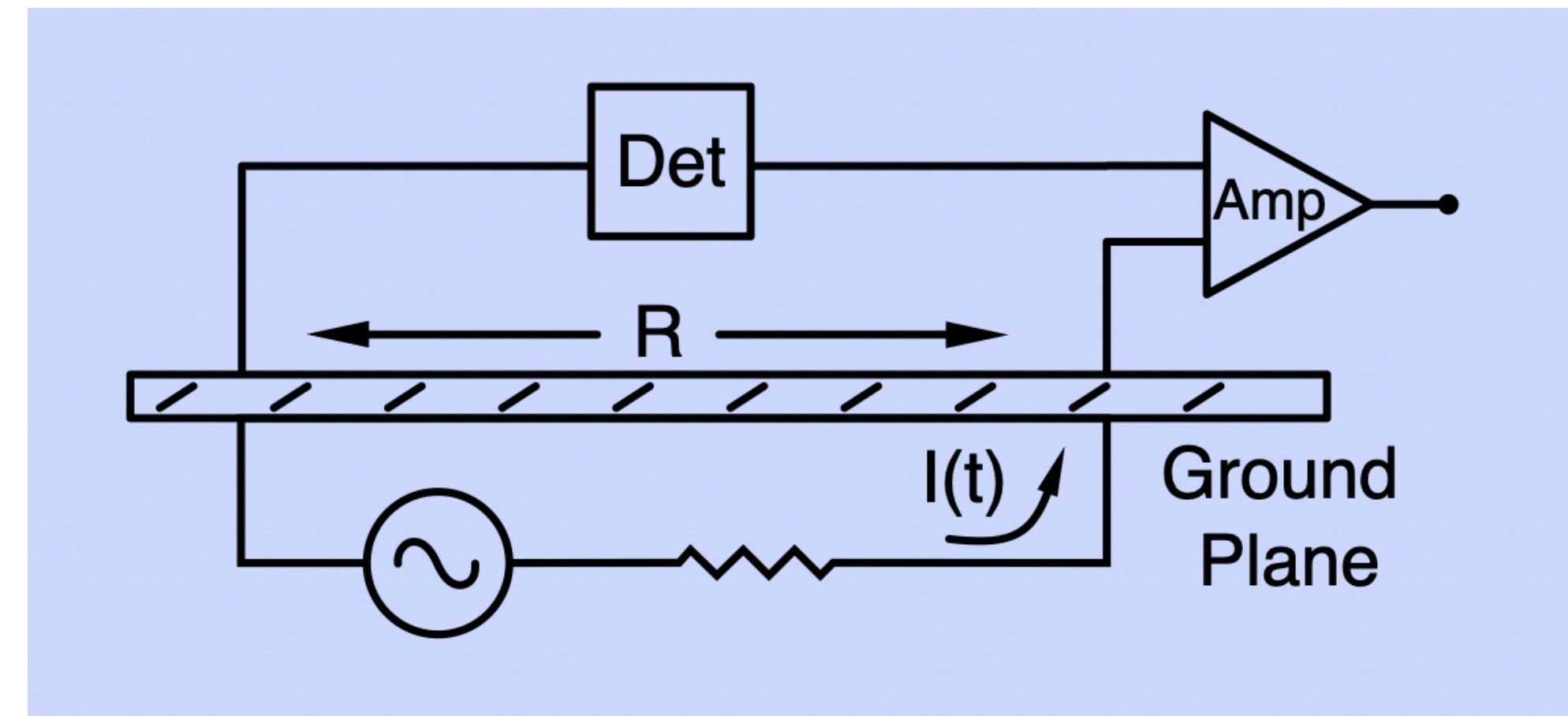
Cure: use twisted pairs or coaxial cables

Examples of extrinsic noise sources

Resistive couplings: ground loops

- * Currents through common connections can give rise to noisy voltages. E.g. the detector can be contaminated by the noise on the ground bus.

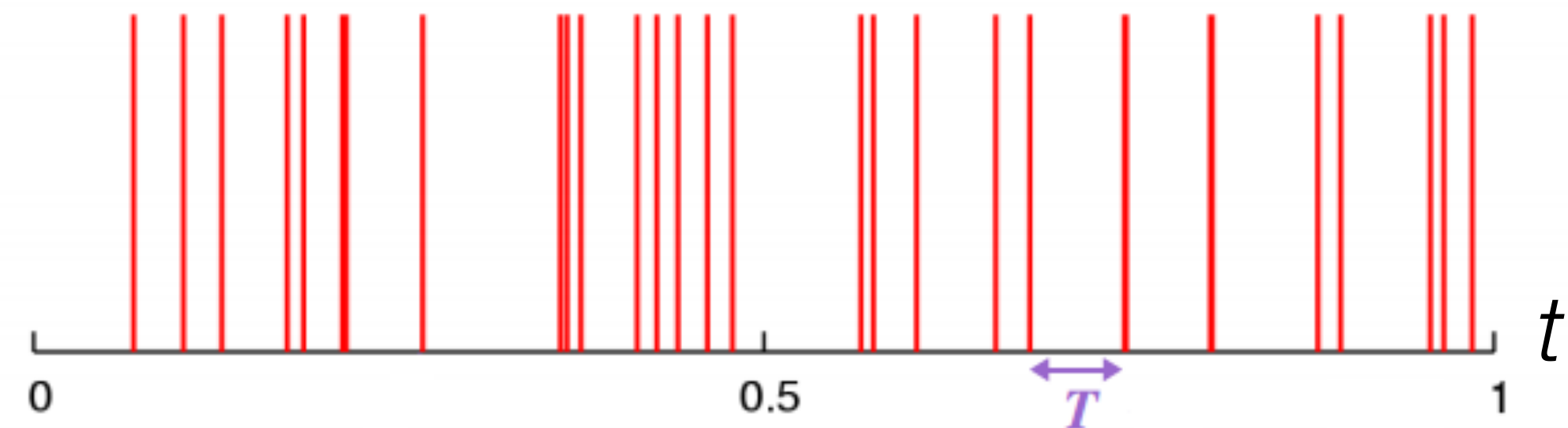
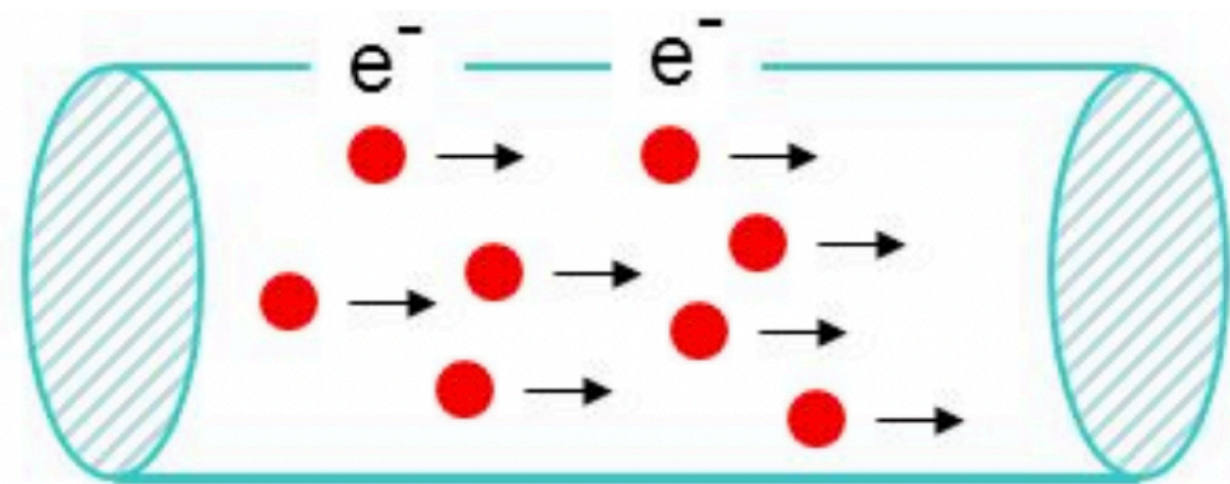
Cure: ground all instruments to the same point, remove sources of large currents from ground wires used for small signals!



Examples of intrinsic noise sources

Shot noise

- * Light and electrical charge are quantized: so the number of photons or electrons which pass a point during a period of time are subject to Poissonian statistical fluctuations.



→ if the signal mean is M photons, the standard deviation (noise) will be \sqrt{M} , hence the $S/N = M/\sqrt{M} = \sqrt{M}$.

- * M may be increased by increasing the photon rate (laser power) or increasing the integration time.

Examples of intrinsic noise sources

Johnson-Nyquist noise (or thermal noise)

- * In a conductor there are a large number of moving electrons. Point-by-point their density shows statistical fluctuations at finite temperature as a function of time, like the local density of air in a given point of a room. These density fluctuations give rise to voltage fluctuations:

$$V_{\text{JN,rms}} = 4k_B R T \Delta f$$

where R is resistance of the conductor, k_B is Boltzmann's constant, T is the temperature, and Δf is the bandwidth over which the noise is measured.

- * This is a *white* noise, since its PSD does not depend on the frequency, i.e. this noise contains Fourier components at any frequency. Example: for $1\text{M}\Omega$ resistor the J-N noise is $V_{\text{JN,rms}} \simeq 100\mu\text{V}$ between 0 and 100 kHz

Examples of intrinsic noise sources

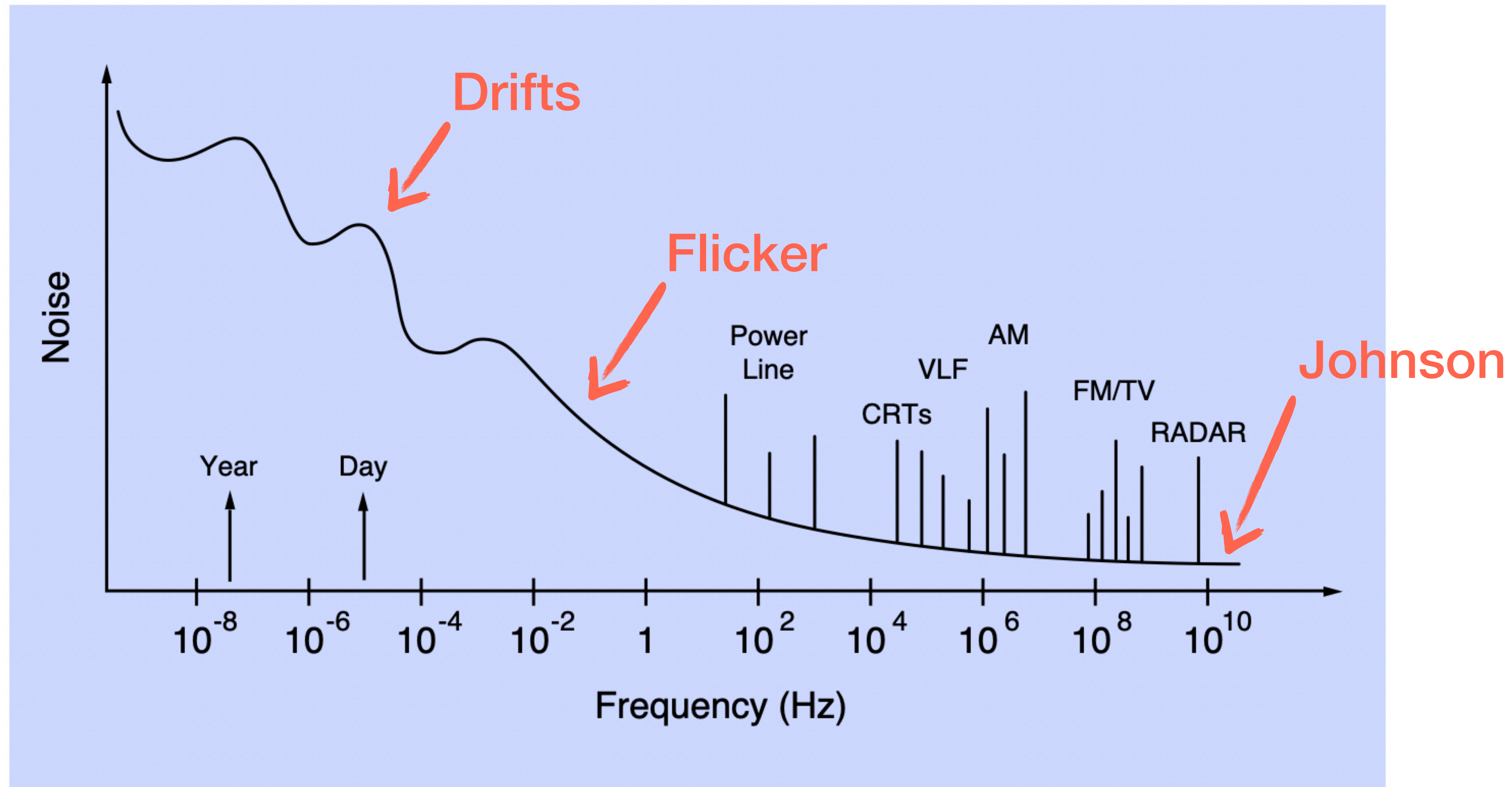
Flicker noise (or 1/f noise)

- * The voltage across a resistor carrying a constant current will fluctuate because the resistance of the material used in the resistor fluctuates, giving rise to a frequency-dependent noise. However, there is no general accepted theory that explains it in all the cases where the 1/f noise is present. It occurs in almost all electronic devices:

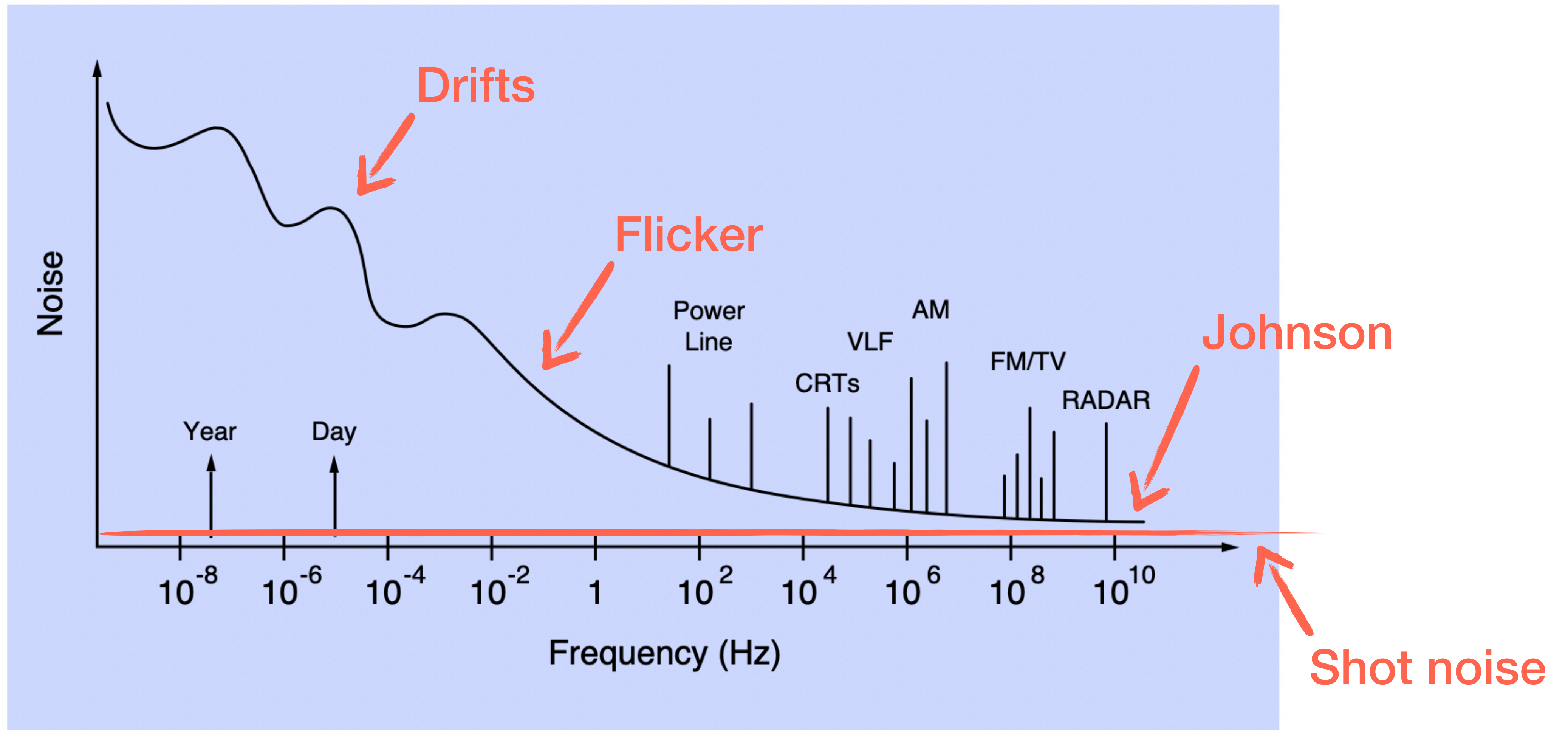
$$V_{\text{pink,rms}}^2 \propto \Delta f / f$$

- * This is a *pink* noise, and it will impact mostly the low-frequency part of the noise spectral density

Examples of noise sources



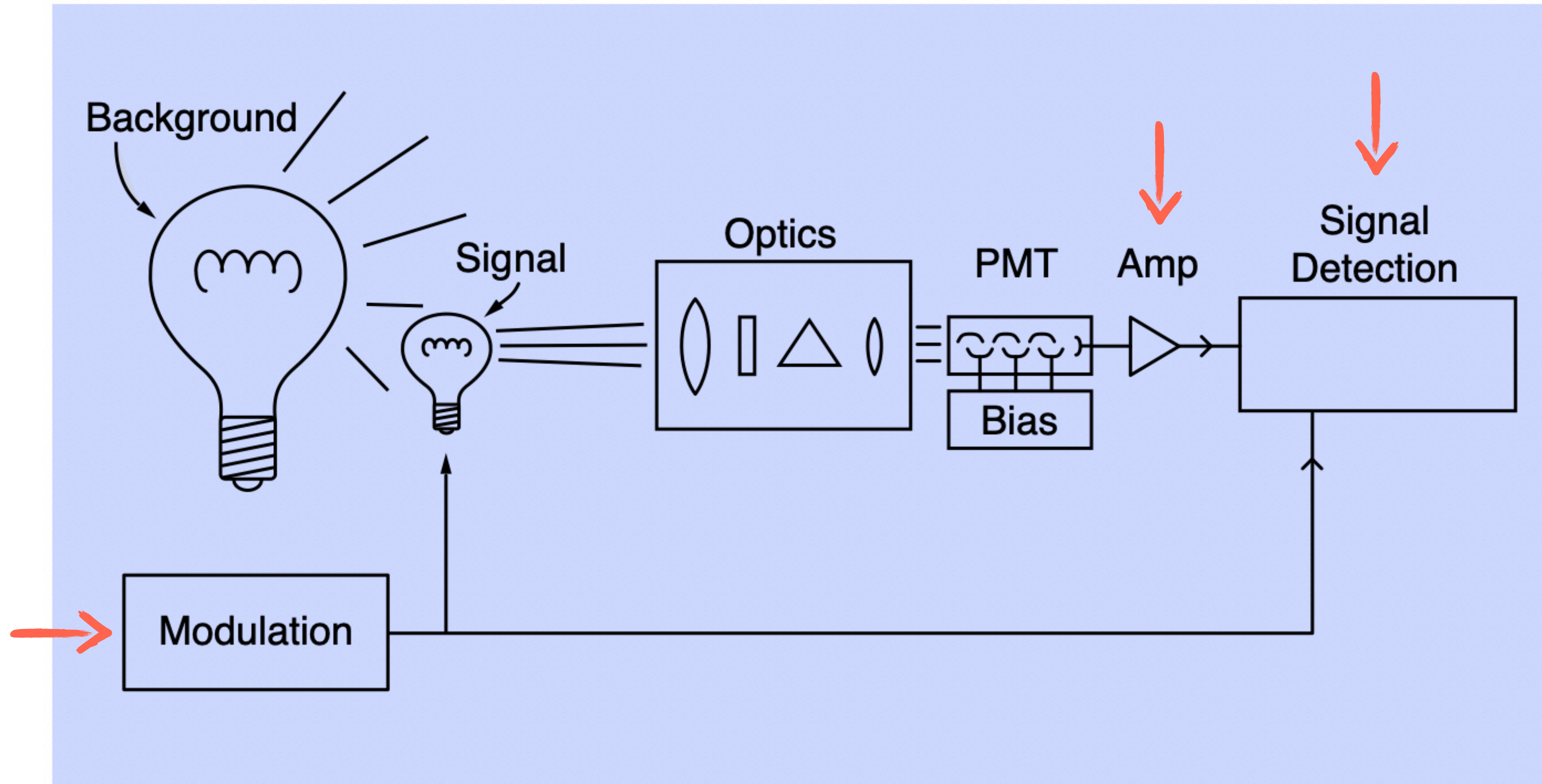
Examples of noise sources



Measuring small signals: amplifiers

- * Several considerations are involved in choosing the correct amplifier for a particular application: bandwidth, gain, impedance, noise characteristics...
- * General technique: perform AC measurements to avoid noise close to DC frequencies → Modulate the source and analyse at the modulation frequency
- * When the source is modulated, one may choose from gated integrators, boxcar averagers, transient digitizers, lock-in amplifiers, spectrum analyzers... We will only use the **lock-in amplifier**
 - Lock-in amplifiers are used to detect and measure very small AC signals... all the way down to a few nV!

Prototype experiment

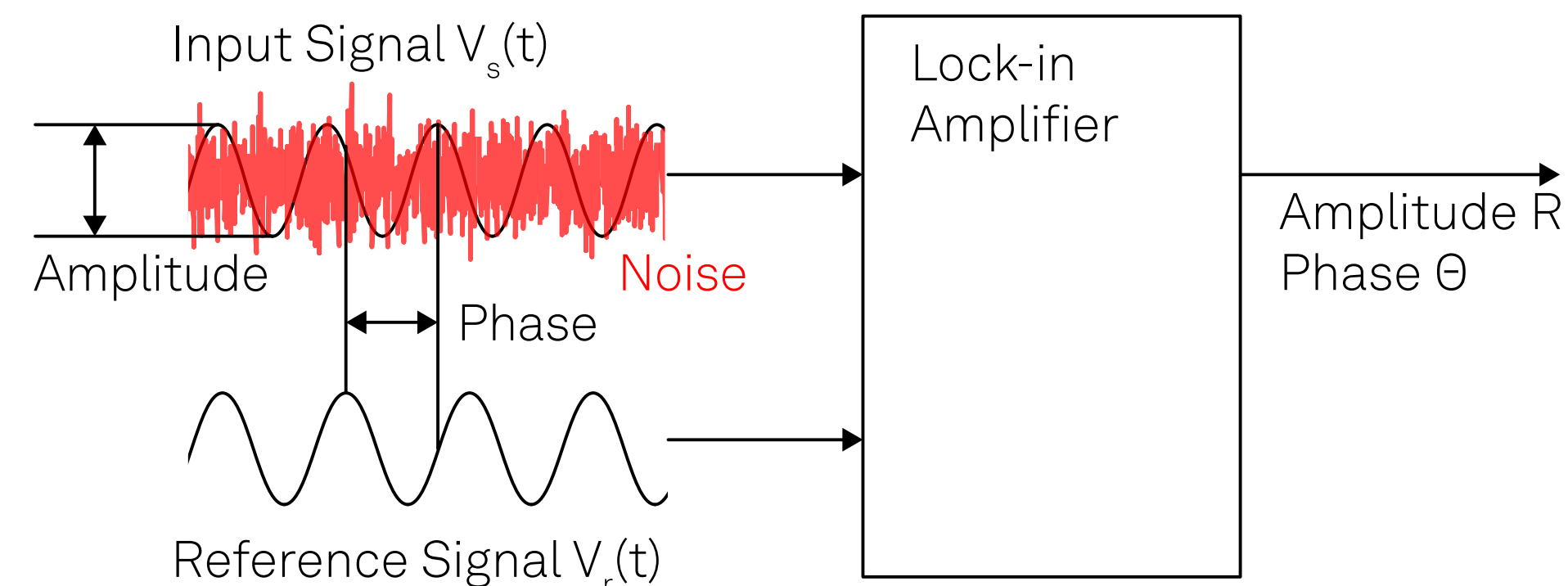


Let's see an example...

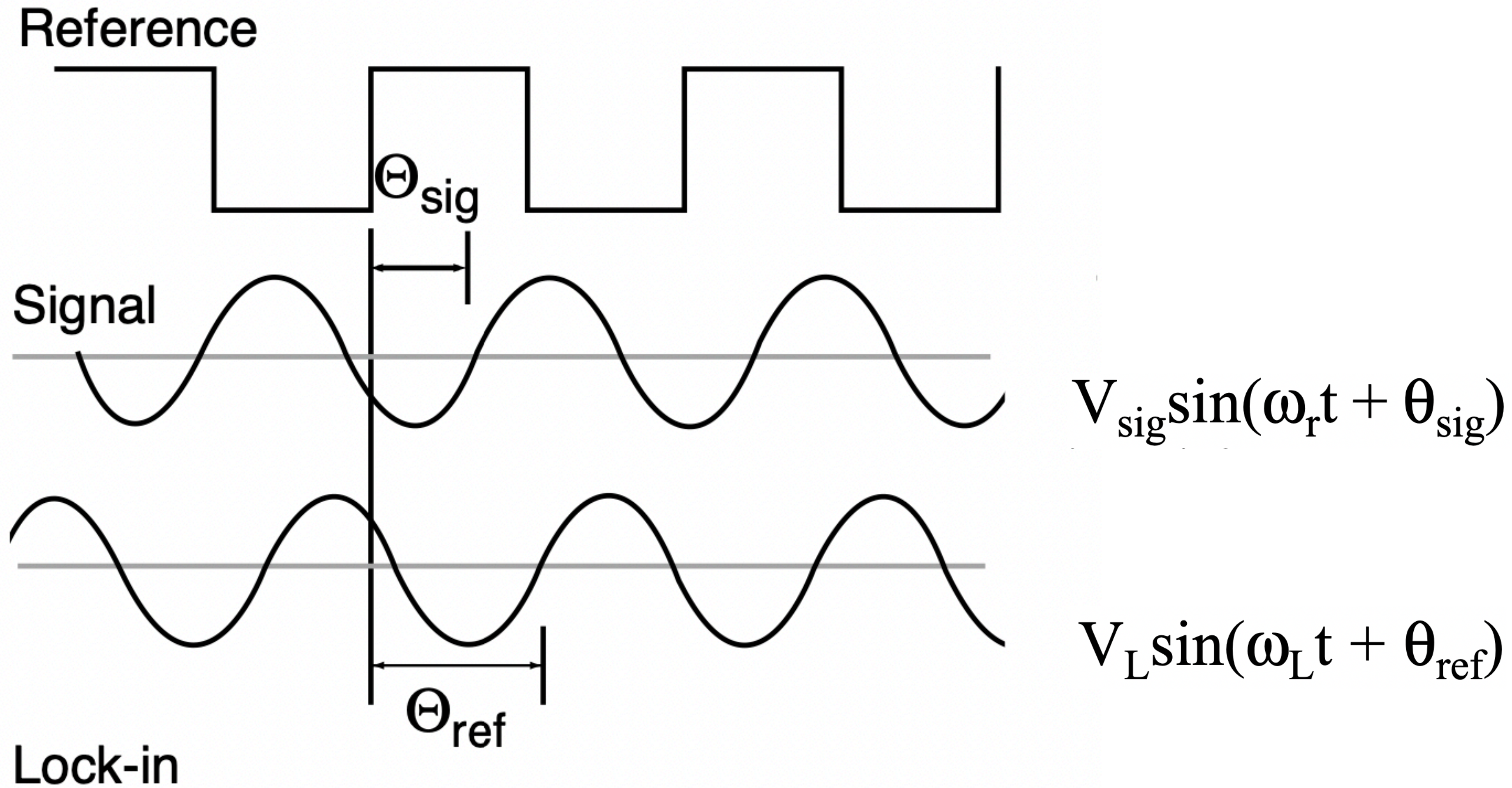
- * Suppose the signal is a 10 nV sine wave at 10 kHz. Clearly some amplification is required to bring the signal above the noise. A very good low-noise amplifier will have about 5 nV/ $\sqrt{\text{Hz}}$ of input noise.
- * If the amplifier bandwidth is 100 kHz and the gain is 1000, we can expect our output to be 10 μV of signal (10 nV \times 1000) and 1.6 mV of broadband noise (5 nV/ $\sqrt{\text{Hz}}$ \times $\sqrt{100 \text{ kHz}}$ \times 1000) 😞
- * Supposing we know the frequency of our signal, we follow the amplifier with a very good band-pass filter with a Q=100 centered at 10 kHz. Any signal in a 100 Hz bandwidth will be detected (10 kHz/Q). The noise in the filter pass band will be 50 μV (5 nV/ $\sqrt{\text{Hz}}$ \times $\sqrt{100\text{Hz}}$ \times 1000), and the signal will still be 10 μV .
 - The output noise is much greater than the signal! 😞

Phase-sensitive detection

- * An amplifier with a phase-sensitive detector can detect the signal at 10 kHz with a bandwidth as narrow as 0.01 Hz: in our previous example, the noise in the detection bandwidth will be $0.5 \mu\text{V}$ ($5 \text{ nV}/\sqrt{\text{Hz}} \times \sqrt{0.01 \text{ Hz}} \times 1000$), while the signal is still $10 \mu\text{V}$ 😊
- * How to achieve this? Lock-in measurements require a **frequency reference**. Typically, an experiment is excited at a fixed modulation frequency, and the lock-in detects the response from the experiment only at the reference frequency.



Phase-sensitive detection



Phase-sensitive detection

- * The lock-in amplifies the signal and then multiplies it by the lock-in reference using a phase-sensitive multiplier (a mixer). The output is simply the product of two sine waves:

$$\begin{aligned}V_{\text{out}} &= V_{\text{sig}} V_L \sin(\omega_r t + \theta_{\text{sig}}) \sin(\omega_L t + \theta_{\text{ref}}) \\ &= \frac{1}{2} V_{\text{sig}} V_L \cos([\omega_r - \omega_L]t + \theta_{\text{sig}} - \theta_{\text{ref}}) - \\ &\quad \frac{1}{2} V_{\text{sig}} V_L \cos([\omega_r + \omega_L]t + \theta_{\text{sig}} + \theta_{\text{ref}})\end{aligned}$$

- * The output is composed by two AC signals, one at the difference-frequency ($\omega_r - \omega_L$) and the other at the sum-frequency ($\omega_r + \omega_L$). If the output is further passed through a low-pass filter, the high-frequency signal (2nd term above) will be removed.
- * What will be left? Let's consider the case in which $\omega_L = \omega_r \dots$

Lock-in amplification

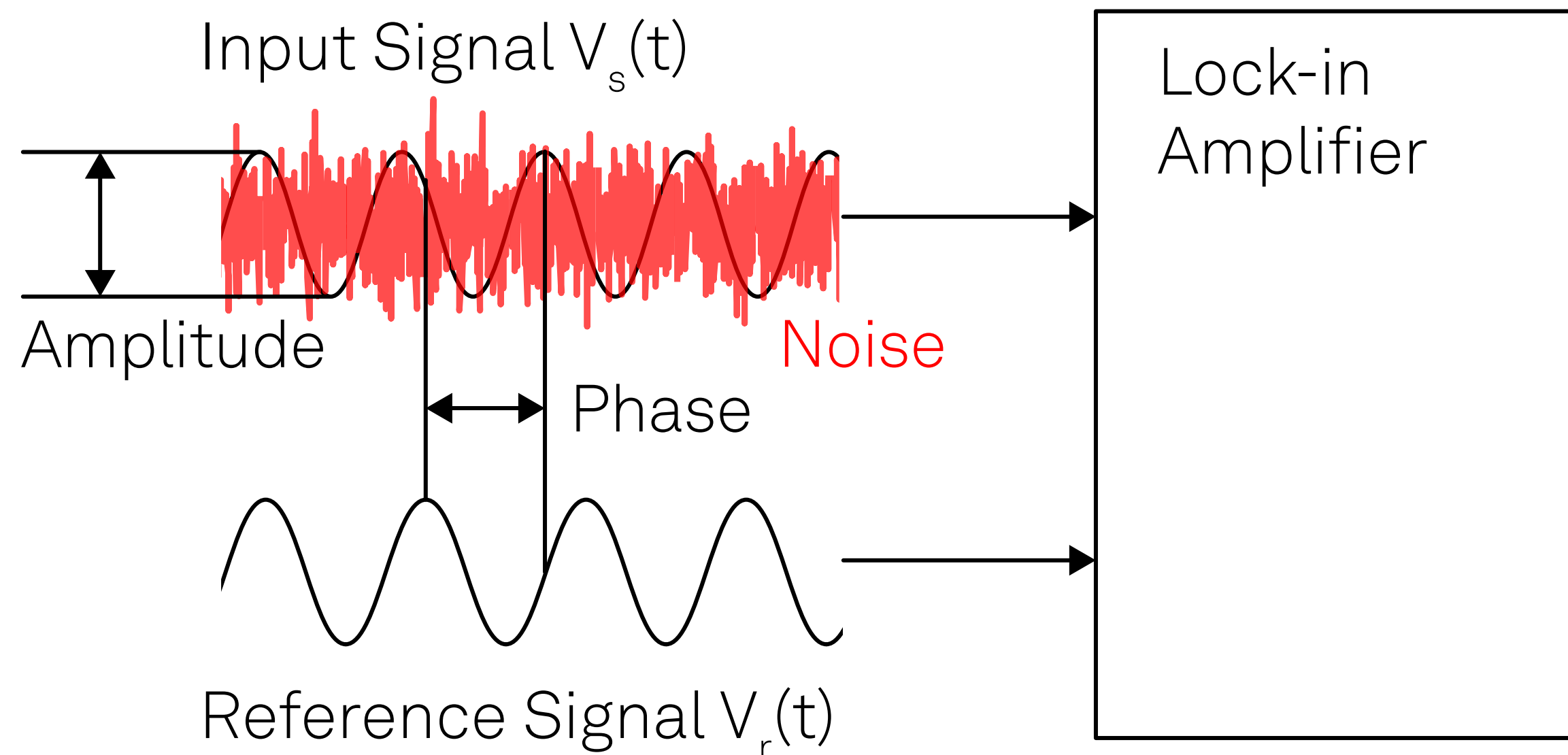
- * If ω_L equals ω_r , the difference-frequency component will be a DC signal!
In this case, the filtered output will be:

$$V_{\text{out}} = \frac{1}{2} V_{\text{sig}} V_L \cos(\theta_{\text{sig}} - \theta_{\text{ref}})$$

- * This is a very nice output — it is a **DC voltage** proportional to the original sinusoidal signal amplitude V_{sig} 😊

We have converted the signal at the modulation frequency ω_L into a DC signal, while signals at any other frequency are attenuated by the filtering.

Lock-in amplification



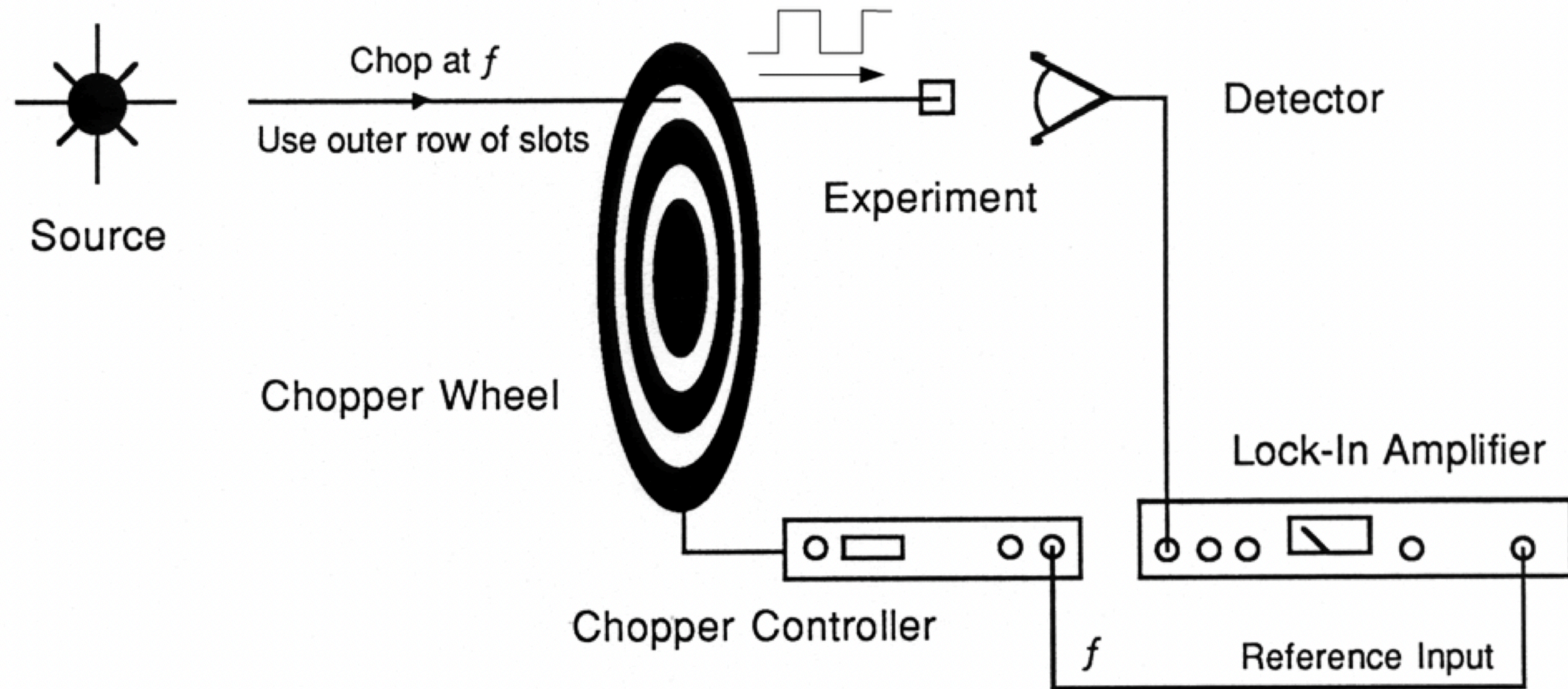
- * A narrower filter will remove noise sources very close to the reference frequency; a wider bandwidth allows some signals to pass → The low-pass filter bandwidth determines the remaining noise, at the expenses of longer integration

- * Let's now take the input signal as composed of signal + noise
- * The lock-in and the low-pass filter only detect signals whose frequencies are very close to the lock-in reference frequency
- * Noise signals, at frequencies far from the reference, are attenuated by the low pass filter, since $\omega_{\text{noise}} - \omega_r$ and $\omega_{\text{noise}} + \omega_r$ are not close to 0.

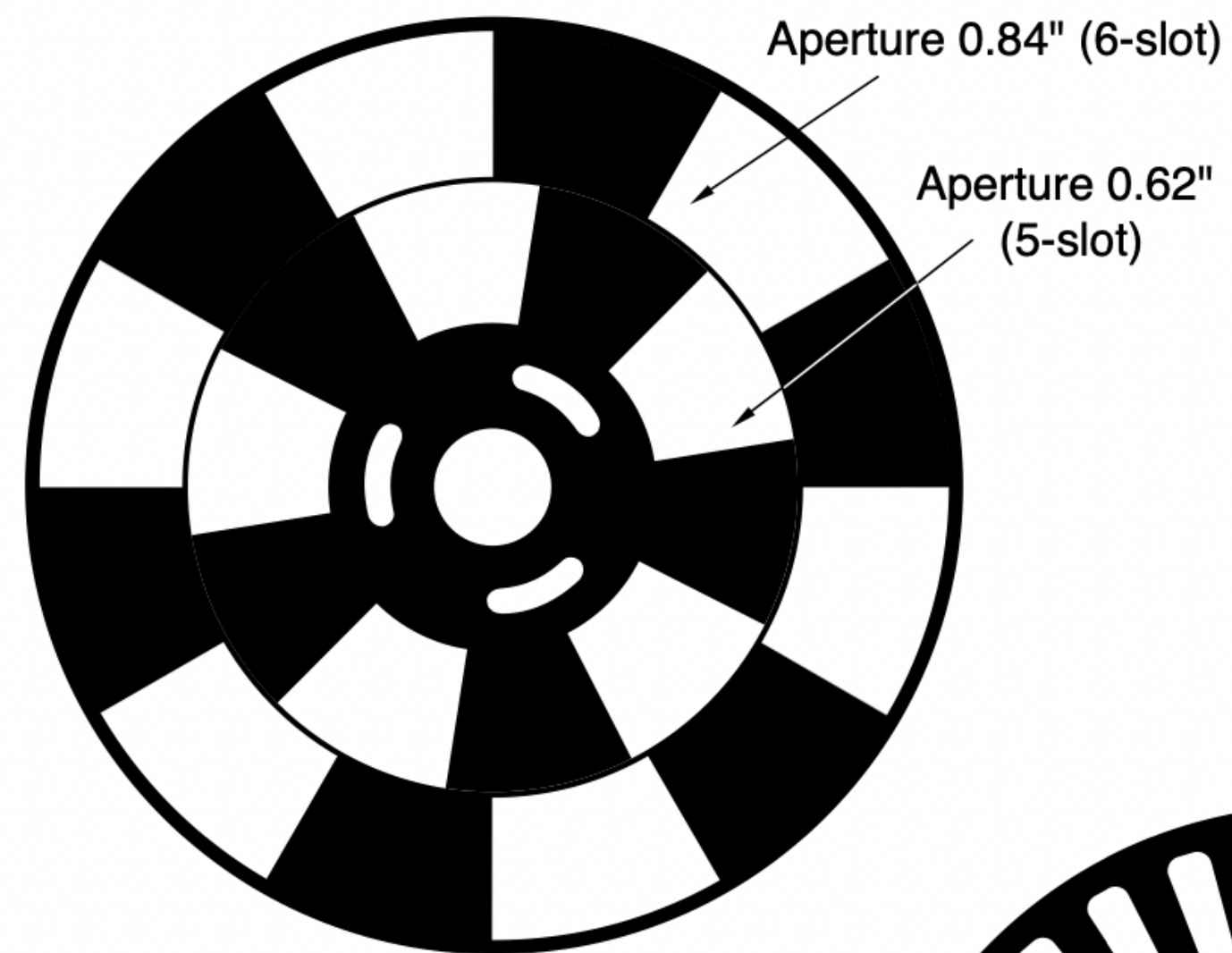
The phase

- * We need to make the lock-in reference the same as the signal frequency, i.e. $\omega_L = \omega_r$. Not only the frequencies need to be the same, also **the phase between the signals can not change over time**. Otherwise, $\cos(\theta_{\text{sig}} - \theta_{\text{ref}})$ will change and the output will not be a DC signal.
 - In other words, the lock-in reference needs to be phase-locked to the signal reference.
- * The lock-in amplifier generates a signal internally, in phase with the frequency reference wave. Let's call θ the phase difference between the signal and the lock-in reference oscillator. By adjusting θ_{ref} we can have $\theta = 0$, in which case we can measure V_{sig} , since $\cos \theta = 1$. Conversely, if θ is 90° , there will be no output at all.
 - This fact can be used in practice to tune the lock-in phase.

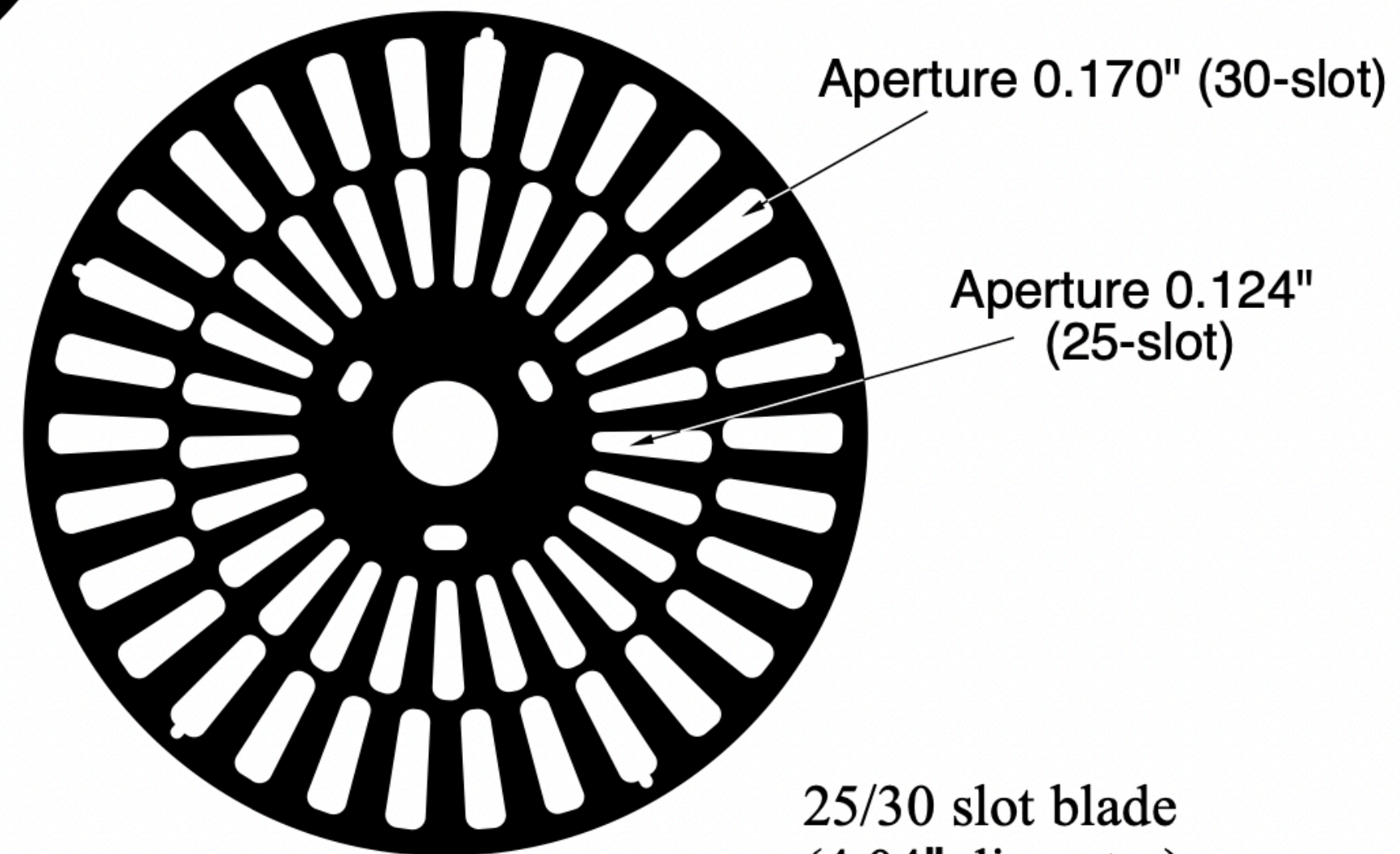
Experimental scheme



Optical choppers



5/6 slot blade
(4.04" diameter)



25/30 slot blade
(4.04" diameter)

